



PCN #: JAON-06DZOX216

Date
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**Qualification of an additional fabrication site for LND150 and
LND250 Supertex device families.**

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QUALIFICATION DATA

High Temperature Operating Life: High Temperature Reverse Bias (HTRB)

Test Method	Mil-STD 750, M1042, Condition A
Test Condition	150°C / 1000 hours
Sample Size (45 ea. min)	(Fail/Pass)
Lot 1	0/45 ^a

^a Pre & Post testing was conducted at room temperature, ~25°C.

High Temperature Operating Life: High Temperature Gate Bias (HTGB)

Test Method	Mil-STD 750, M1042, Condition B
Test Condition	150°C / 1000 hours
Sample Size (45 ea. min)	(Fail/Pass)
Lot 1	0/45 ^a

^a Pre & Post testing was conducted at room temperature, ~25°C.

ESD

Test	Pin Combination	Sample Size	Pass Voltage
ESD-HBM	Gate to Drain/Source ^a	Lot 1 = 9 ^a	±0.9kV ^b
ESD-HBM	Drain to Gain/Source ^a	Lot 1 = 9 ^a	±2.7kV ^b
ESD-HBM	Source to Drain/Gate	Lot 1 = 12 ^a	±2.4kV ^b
ESD-HBM	Gate to Source ^a	Lot 1 = 6 ^a	±0.8kV ^b
ESD-HBM	Gate to Drain ^a	Lot 1 = 6 ^a	±0.9kV ^b

^a Class 1B as per the Mil-Std 750 M1020

^b Pre & Post testing was conducted at room temperature, ~25°C